

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

50478-2000

Application Number

10577079
Not yet assigned

Applicant(s)

Shinichi Yamamoto et al

Filing Date

Herewith

Group Art Unit

Not yet assigned

U. S. PATENT DOCUMENTS

| EXAMINER INITIAL | REF | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
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| /Z.S./ | | 6,34,6775 | 2.12.2002 | Lee, et al. | | | |
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U. S. PATENT APPLICATION PUBLICATIONS

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FOREIGN PATENT DOCUMENTS

| | REF | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | Translation | |
|--------|-----|-----------------|------------|---|-------|----------|-------------|----|
| | | | | | | | YES | NO |
| /Z.S./ | | 2002-117771 | 4.19.2002 | Japan w/English Abstract | | | X | |
| /Z.S./ | | 2004-335406 | 11.25.2004 | Japan w/English Abstract | | | X | |
| /Z.S./ | | 08-339767 | 12.24.1996 | Japan w/English Abstract | | | X | |
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| /Z.S./ | Whikun Yi et al.; Secondary Electron Emission Yields from MgO deposited on Carbon Nanotubes; Journal of Applied Physics; Vol 89, No. 7; 2001 American Institute of Physics. |
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EXAMINER /Zachary Snyder/

DATE CONSIDERED 07/03/2008

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